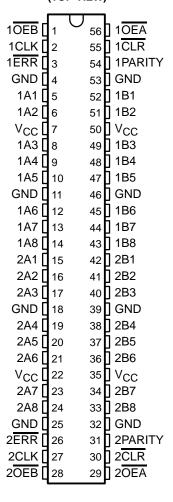
SCAS166A - JUNE 1990 - REVISED APRIL 1996

- Members of the Texas Instruments
 Widebus™ Family
- Inputs Are TTL-Voltage Compatible
- Parity Error Flag With Parity Generator/Checker
- Register for Storage of the Parity Error Flag
- Flow-Through Architecture Optimizes PCB Layout
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-μm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include 300-mil Shrink Small-Outline (DL) Packages Using 25-mil Center-to-Center Pin Spacings and 380-mil Fine-Pitch Ceramic Flat (WD) Packages Using 25-mil Center-to-Center Pin Spacings

description

The 'ACT16833 consist of two noninverting 8-bit to 9-bit parity bus transceivers and are designed for communication between data buses. For each transceiver, when data is transmitted from the A bus to the B bus, an odd-parity bit is generated and output on the parity I/O pin (1PARITY or 2PARITY). When data is transmitted from the B bus to the A bus, 1PARITY or 2PARITY is configured as an input and combined with the B-input data to generate an active-low error flag if odd parity is not detected.

54ACT16833 . . . WD PACKAGE 74ACT16833 . . . DL PACKAGE (TOP VIEW)



The error (1ERR or 2ERR) output is configured as an open-collector output. The B-to-A parity error flag is clocked into 1ERR or 2ERR on the low-to-high transition of the clock (1CLK or 2CLK) input. 1ERR or 2ERR is cleared (set high) by taking the clear (1CLR or 2CLR) input low.

The output-enable (\overline{OEA} and \overline{OEB}) inputs can be used to disable the device so that the buses are effectively isolated. When both \overline{OEA} and \overline{OEB} are low, data is transferred from the A bus to the B bus and inverted parity is generated. Inverted parity is a forced error condition that gives the designer more system diagnostic capability.

The 74ACT16833 is packaged in TI's shrink small-outline package, which provides twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

The 54ACT16833 is characterized for operation over the full military temperature range of –55°C to 125°C. The 74ACT16833 is characterized for operation from –40°C to 85°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

EPIC and Widebus are trademarks of Texas Instruments Incorporated.

TEXAS INSTRUMENTS

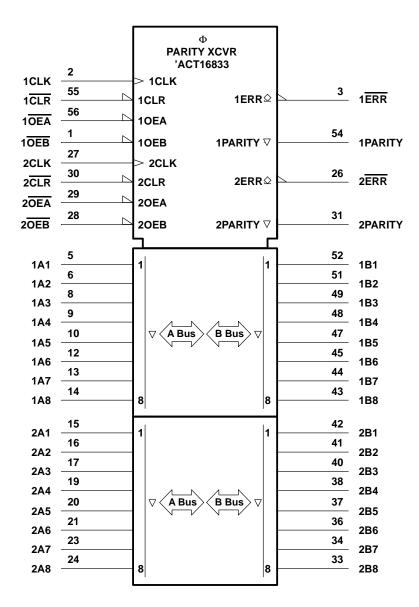
54ACT16833, 74ACT16833 DUAL 8-BIT TO 9-BIT PARITY BUS TRANSCEIVERS

SCAS166A – JUNE 1990 – REVISED APRIL 1996

FUNCTION TABLE	FU	NC	ΓΙΟΝ	ITAB	LE
----------------	----	----	------	------	----

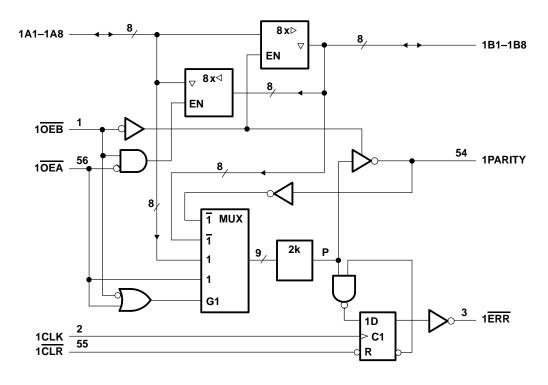
			INPUTS	s			OUTP	UT AND I/C)		7
OEB	OEA	CLR	CLK	Ai Σ OF H	Bi [†] Σ OF H	А	В	PARITY	ERR‡	FUNCTION	
L	Н	Х	Х	Odd Even	NA	NA	Α	L H	NA	A data to B bus and generate parity]
Н	L	Н	↑	NA	Odd Even	В	NA	NA	H L	B data to A bus and check parity	
Х	Х	L	Х	Х	Х	Х	NA	NA	Н	Check error-flag register	1
		Н	No↑	Х					NC		7
н	н	L	No↑	X	V	Z	Z	Z	Н	 '-*\s\ o	1 .
"	П	Н	\uparrow	0	d d		۷	۷	Н		l l a
		Н	1	E v	, e n				L		
L	L	Х	Х	O (d d , e n	N	A	H L	N	A d g e n	a ta
N	Α	=		n o	t	а	р	p I	i	c a b	l e
†s ‡o §i	u i u	m m <u>t</u> p t (a h w	t i wta ihse	o n ss t n m	ар о с	o tr d l		sv i , c ł	n i g h so hu os k Ee Rd R)	- I wlyn s

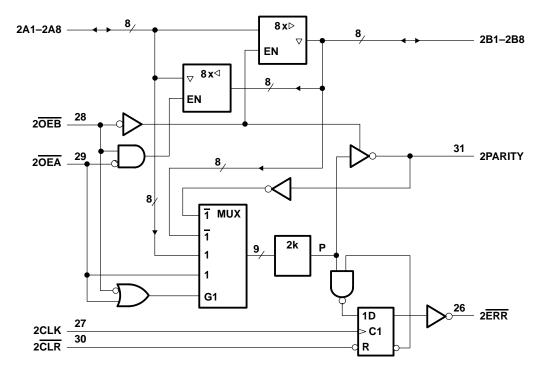
logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)





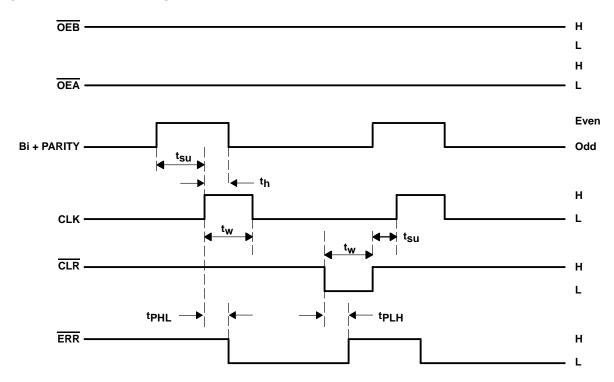


ERROR FLAG FUNCTION TABLE

INP	UTS	INTERNAL TO DEVICE	OUTPUT PRE-STATE	OUTPUT ERR	FUNCTION
CLR	CLK	POINT P‡	ERR _{n-1} †	LIXIX	
Н	1	Н	Н	Н	
Н	1	X	L	L	Sample
Н	1	L	X	L	
L	Х	X	Х	Н	Clear

[†] The state of ERR before any changes at CLR, CLK, or point P

timing waveforms, error flag



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)§

Supply voltage range, V _{CC}	–0.5 V to 7 V
Input voltage range, V _I (see Note 1)–C	$0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, V _O (see Note 1)Output voltage range, V _O (see Note 1)	$0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±50 mA
Continuous current through V _{CC} or GND	±450 mA
Maximum power package dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 2): DL package	1.4 W
Storage temperature range, T _{stg}	–65°C to 150°C

[§] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

^{2.} The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils.



[‡] Location of point P is shown on local diagram.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

54ACT16833, 74ACT16833 DUAL 8-BIT TO 9-BIT PARITY BUS TRANSCEIVERS

SCAS166A - JUNE 1990 - REVISED APRIL 1996

recommended operating conditions (see Note 3)

		54ACT16833			74	33	UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2		7	2			V
VIL	Low-level input voltage		3	0.8			8.0	V
٧ _I	Input voltage	0	PA	VCC	0		VCC	V
۷o	Output voltage	0	7	VCC	0		VCC	V
Іон	High-level output current		57/	-24			-24	mA
loL	Low-level output current		5	24			24	mA
Δt/Δν	Input transition rise or fall rate	0.		10	0		10	ns/V
T _A	Operating free-air temperature	– 55		125	-40		85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DA.	DAMETER	TEST COMPLETIONS	V	T,	Δ = 25°C	;	54ACT	16833	74ACT	16833	UNIT
l PA	RAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
ЮН	ERR	$V_O = V_{CC}$	5.5 V			0.5		5		5	μΑ
		Jan - 50 u A	4.5 V	4.4			4.4		4.4		
	.	I _{OH} = -50 μA	5.5 V	5.4			5.4		5.4		
Vон	All outputs except ERR	1011 - 24 mA	4.5 V	3.94			3.8		3.8		V
	oxoopt Erit	I _{OH} = -24 mA	5.5 V	4.94			4.8		4.8		
		$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V				3.85		3.85		
		I _{OL} = 50 μA	4.5 V			0.1		0.1		0.1	
	ΙΟΣ = 30 μΑ	5.5 V			0.1		0.1		0.1		
VOL		I _{OL} = 24 mA	4.5 V			0.36		0.44		0.44	V
		10L = 24 111A	5.5 V			0.36	Ç)	0.44		0.44	
		I _{OL} = 75 mA [†]	5.5 V				700	1.65		1.65	
lį	A or B ports	$V_I = V_{CC}$ or GND	5.5 V			±0.1	A)	±1		±1	μΑ
loz‡	Control inputs	$V_O = V_{CC}$ or GND	5.5 V			±0.5		±5		±5	μΑ
ICC		$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		80		80	μΑ
ΔlCC§		One input at 3.4 V, Other inputs at V _{CC} or GND	5.5 V			0.9		1		1	mA
Ci	Control inputs	V _I = V _{CC} or GND	5 V		3.5						pF
C _{io}	A or B ports, PARITY	$V_O = V_{CC}$ or GND	5 V		11.5						pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.



For I/O ports, the parameter IOZ includes the input leakage current.

[§] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or VCC.

SCAS166A - JUNE 1990 - REVISED APRIL 1996

timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1 and timing waveforms)

					54ACT16833		74ACT16833		UNIT	
			MIN	MAX	MIN	MAX	MIN	MAX	UNIT	
tw Pulse duration		CLK high or low	4		4		4			
t _W	Fulse duration	CLR low	4		4	10,1	4		ns	
Γ.	0	Bi + PARITY	7.5	7.5 7.5 7		7.5				
t _{su}	Setup time before CLK↑	CLR inactive	1.5		1.5		1.5		ns	
th	Hold time, Bi + PARITY low after CLK↑		0		0		0		ns	

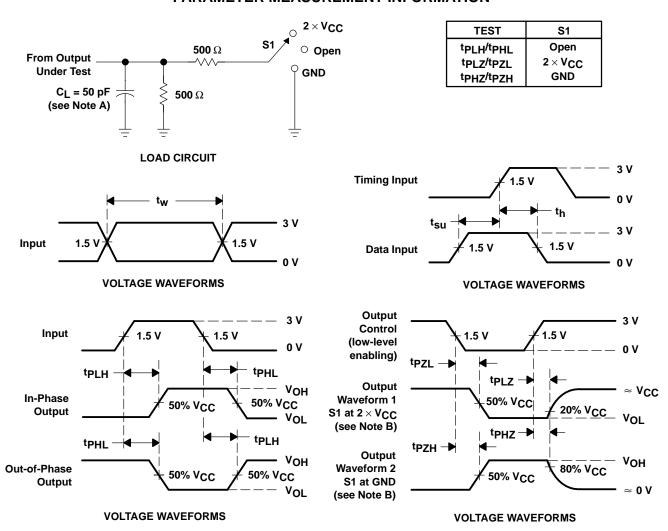
switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1 and timing waveforms)

PARAMETER	FROM	то	Т,	գ = 25°C	;	54ACT	16833	74ACT	16833	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
^t PLH	A or B	B or A	4	7.2	9.2	4	10.4	4	10.4	ns
^t PHL	AOIB	BUIA	3.2	6.6	9.6	3.2	10.7	3.2	10.7	115
^t PLH	А	PARITY	3.9	7.9	12	3.9	13.5	3.9	13.5	ns
t _{PHL}	A	FARITI	4.2	8.3	12.4	4.2	13.8	4.2	13.8	115
^t PZH	OEB or OEA	A or B	3.1	6.7	10.1	3.1	11.2	3.1	11.2	ns
^t PZL	OEB of OEA	AUB	3.8	7.9	11.6	3.8	13	3.8	13	115
^t PHZ	OEB or OEA	A or B	5.5	7.8	10	5.5	10.8	5.5	10.8	ns
t _{PLZ}	OEB of OEA	AUB	5	7.1	9.3	5	10.1	5	10.1	10.1
^t PLH	CLR	ERR	10.7	13.1	15.4	10.7	15.8	10.7	15.8	ns
^t PHL	CLK	EKK	4.6	7.8	10.3	4.6	11.6	4.6	11.6	115
^t PLH	OEA	PARITY	4	8	11.8	4 0 8	13.2	4	13.2	ns
^t PHL	OEA	FARITI	4.3	8.5	12.3	4.3	13.6	4.3	13.6	115
^t PZH	<u> </u>	PARITY	2.6	5.7	8.5	2.6	9.5	2.6	9.5	ns
tPZL	OEB	PARITY	3.4	6.8	9.8	3.4	10.7	3.4	10.7	115
^t PHZ	<u> </u>	PARITY	5.6	7.9	9.5	5.6	10.2	5.6	10.2	ne
^t PLZ	ŌEB	FARIIT	5.1	7.2	9.1	5.1	9.7	5.1	9.7	ns

operating characteristics, V_{CC} = 5 V, T_A = 25°C

	PARAMETER	TEST CO	TYP	UNIT			
		Outpute enabled	A to B			64	
	Power dissipation capacitance per transceiver	Outputs enabled	B to A	CL = 50 pF,	4 A MILL	72	pF
C _{pd}		Outroute disabled	A to B		f = 1 MHz	6	рг
		Outputs disabled	B to A			10.5	

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_I includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \ \Omega$, $t_f = 3 \ ns$, $t_f = 3 \ ns$.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.

Copyright © 1996, Texas Instruments Incorporated